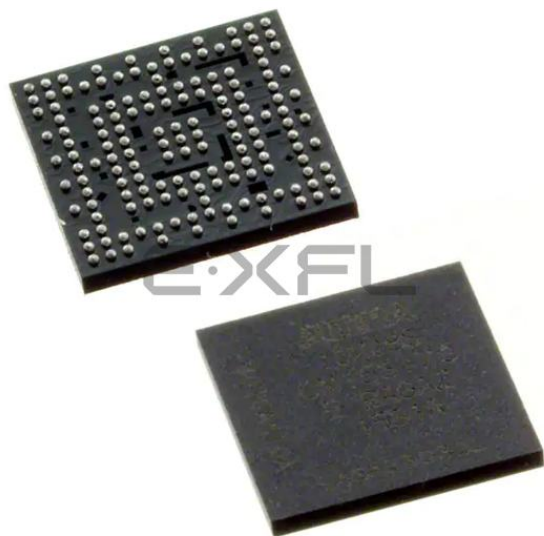




Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

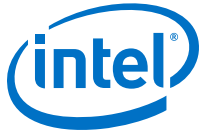
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	125
Number of Logic Elements/Cells	2000
Total RAM Bits	110592
Number of I/O	112
Number of Gates	-
Voltage - Supply	2.85V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	153-VFBGA
Supplier Device Package	153-MBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m02scm153i7g



Operating Conditions

Intel MAX 10 devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Intel MAX 10 devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Intel MAX 10 devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions outside the range listed in the absolute maximum ratings tables may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Single Supply Devices Absolute Maximum Ratings

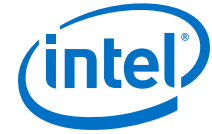
Table 2. Absolute Maximum Ratings for Intel MAX 10 Single Supply Devices

Symbol	Parameter	Min	Max	Unit
V _{CC_ONE}	Supply voltage for core and periphery through on-die voltage regulator	-0.5	3.9	V
V _{CCIO}	Supply voltage for input and output buffers	-0.5	3.9	V
V _{CCA}	Supply voltage for phase-locked loop (PLL) regulator and analog-to-digital converter (ADC) block (analog)	-0.5	3.9	V

Dual Supply Devices Absolute Maximum Ratings

Table 3. Absolute Maximum Ratings for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Min	Max	Unit
V _{CC}	Supply voltage for core and periphery	-0.5	1.63	V
V _{CCIO}	Supply voltage for input and output buffers	-0.5	3.9	V
V _{CCA}	Supply voltage for PLL regulator (analog)	-0.5	3.41	V
continued...				



DC Characteristics

Supply Current and Power Consumption

Intel offers two ways to estimate power for your design—the Excel-based Early Power Estimator (EPE) and the Intel Quartus Prime Power Analyzer feature.

Use the Excel-based EPE before you start your design to estimate the supply current for your design. The EPE provides a magnitude estimate of the device power because these currents vary greatly with the usage of the resources.

The Intel Quartus Prime Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yield very accurate power estimates.

Related Information

- [Early Power Estimator User Guide](#)
Provides more information about power estimation tools.
- [Power Analysis chapter, Intel Quartus Prime Handbook](#)
Provides more information about power estimation tools.

I/O Pin Leakage Current

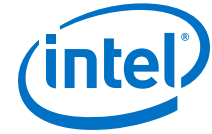
The values in the table are specified for normal device operation. The values vary during device power-up. This applies for all V_{CCIO} settings (3.3, 3.0, 2.5, 1.8, 1.5, 1.35, and 1.2 V).

10 μ A I/O leakage current limit is applicable when the internal clamping diode is off. A higher current can be the observed when the diode is on.

Input channel leakage of ADC I/O pins due to hot socket is up to maximum of 1.8 mA. The input channel leakage occurs when the ADC IP core is enabled or disabled. This is applicable to all Intel MAX 10 devices with ADC IP core, which are 10M04, 10M08, 10M16, 10M25, 10M40, and 10M50 devices. The ADC I/O pins are in Bank 1A.

Table 10. I/O Pin Leakage Current for Intel MAX 10 Devices

Symbol	Parameter	Condition	Min	Max	Unit
I_I	Input pin leakage current	$V_I = 0 \text{ V to } V_{CCIO\text{MAX}}$	-10	10	μA
I_{OZ}	Tristated I/O pin leakage current	$V_O = 0 \text{ V to } V_{CCIO\text{MAX}}$	-10	10	μA



Series OCT without Calibration Specifications

Table 13. Series OCT without Calibration Specifications for Intel MAX 10 Devices

This table shows the variation of on-chip termination (OCT) without calibration across process, voltage, and temperature (PVT).

Description	V _{CCIO} (V)	Resistance Tolerance		Unit
		-C7, -I6, -I7, -A6, -A7	-C8	
Series OCT without calibration	3.00	±35	±30	%
	2.50	±35	±30	%
	1.80	±40	±35	%
	1.50	±40	±40	%
	1.35	±40	±50	%
	1.20	±45	±60	%

Series OCT with Calibration at Device Power-Up Specifications

Table 14. Series OCT with Calibration at Device Power-Up Specifications for Intel MAX 10 Devices

OCT calibration is automatically performed at device power-up for OCT enabled I/Os.

Description	V _{CCIO} (V)	Calibration Accuracy	Unit
Series OCT with calibration at device power-up	3.00	±12	%
	2.50	±12	%
	1.80	±12	%
	1.50	±12	%
	1.35	±12	%
	1.20	±12	%

OCT Variation after Calibration at Device Power-Up

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up.

Use the following table and equation to determine the final OCT resistance considering the variations after calibration at device power-up.

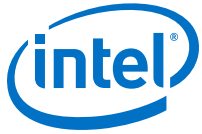


Table 15. OCT Variation after Calibration at Device Power-Up for Intel MAX 10 Devices

This table lists the change percentage of the OCT resistance with voltage and temperature.

Description	Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
OCT variation after calibration at device power-up	3.00	0.25	-0.027
	2.50	0.245	-0.04
	1.80	0.242	-0.079
	1.50	0.235	-0.125
	1.35	0.229	-0.16
	1.20	0.197	-0.208

Figure 1. Equation for OCT Resistance after Calibration at Device Power-Up

$$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV$$

$$\Delta R_T = (T_2 - T_1) \times dR/dT$$

$$\text{For } \Delta R_X < 0; MF_X = 1/(|\Delta R_X|/100 + 1)$$

$$\text{For } \Delta R_X > 0; MF_X = \Delta R_X/100 + 1$$

$$MF = MF_V \times MF_T$$

$$R_{final} = R_{initial} \times MF$$

The definitions for equation are as follows:

- T_1 is the initial temperature.
- T_2 is the final temperature.
- MF is multiplication factor.
- $R_{initial}$ is initial resistance.
- R_{final} is final resistance.

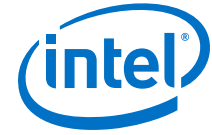
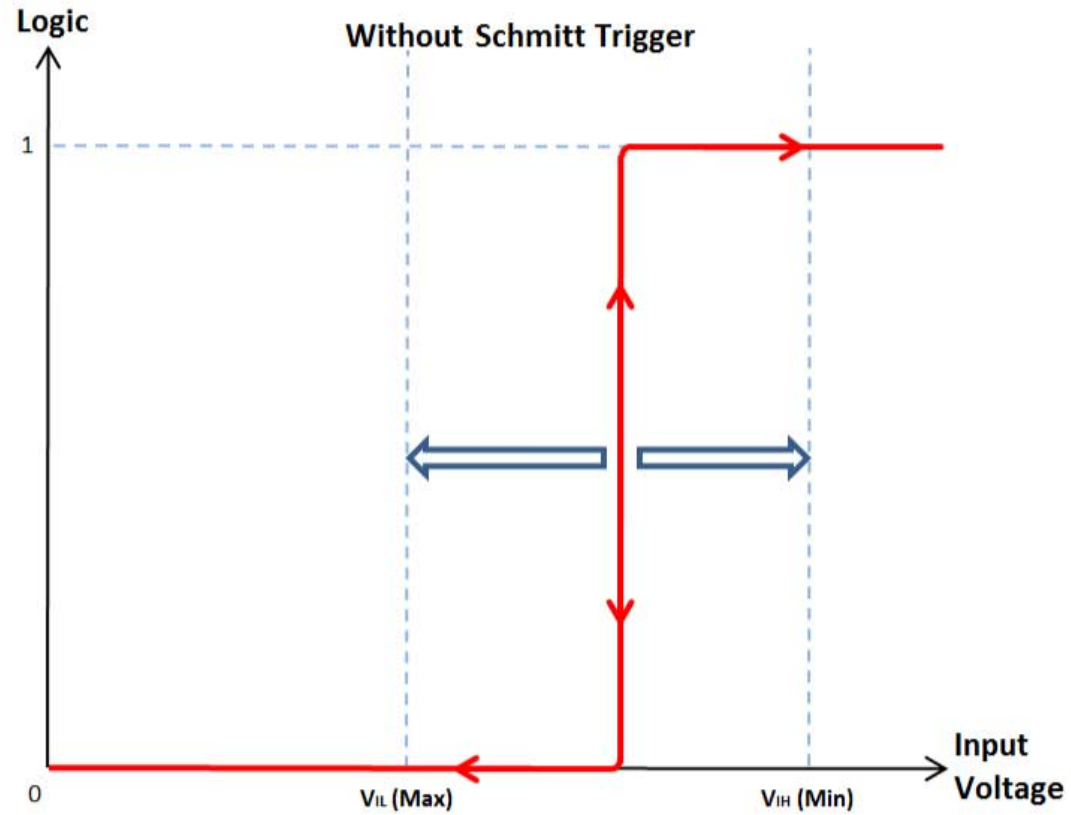
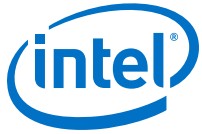


Figure 3. LVTTL/LVCMOS Input Standard Voltage Diagram





Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications

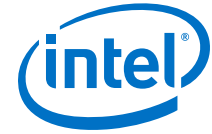
Table 21. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{REF} (V)			V _{TT} (V) ⁽¹⁴⁾		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-15 Class I, II	1.425	1.5	1.575	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
SSTL-135 Class I, II	1.283	1.35	1.45	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 × V _{CCIO} ⁽¹⁵⁾	0.5 × V _{CCIO} ⁽¹⁵⁾	0.52 × V _{CCIO} ⁽¹⁵⁾	—	0.5 × V _{CCIO}	—
				0.47 × V _{CCIO} ⁽¹⁶⁾	0.5 × V _{CCIO} ⁽¹⁶⁾	0.53 × V _{CCIO} ⁽¹⁶⁾			
HSUL-12	1.14	1.2	1.3	0.49 × V _{CCIO}	0.5 × V _{CCIO}	0.51 × V _{CCIO}	—	—	—

⁽¹⁴⁾ V_{TT} of transmitting device must track V_{REF} of the receiving device.

⁽¹⁵⁾ Value shown refers to DC input reference voltage, V_{REF(DC)}.

⁽¹⁶⁾ Value shown refers to AC input reference voltage, V_{REF(AC)}.



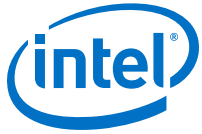
Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications

Table 22. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Intel MAX 10 Devices

To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the SSTL-15 Class I specification (8 mA), you should set the current strength settings to 8 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

I/O Standard	$V_{IL(DC)} (V)$		$V_{IH(DC)} (V)$		$V_{IL(AC)} (V)$		$V_{IH(AC)} (V)$		$V_{OL} (V)$	$V_{OH} (V)$	$I_{OL} (mA)$	$I_{OH} (mA)$
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
SSTL-2 Class I	—	$V_{REF} - 0.18$	$V_{REF} + 0.18$	—	—	$V_{REF} - 0.31$	$V_{REF} + 0.31$	—	$V_{TT} - 0.57$	$V_{TT} + 0.57$	8.1	-8.1
SSTL-2 Class II	—	$V_{REF} - 0.18$	$V_{REF} + 0.18$	—	—	$V_{REF} - 0.31$	$V_{REF} + 0.31$	—	$V_{TT} - 0.76$	$V_{TT} + 0.76$	16.4	-16.4
SSTL-18 Class I	—	$V_{REF} - 0.125$	$V_{REF} + 0.125$	—	—	$V_{REF} - 0.25$	$V_{REF} + 0.25$	—	$V_{TT} - 0.475$	$V_{TT} + 0.475$	6.7	-6.7
SSTL-18 Class II	—	$V_{REF} - 0.125$	$V_{REF} + 0.125$	—	—	$V_{REF} - 0.25$	$V_{REF} + 0.25$	—	0.28	$V_{CCIO} - 0.28$	13.4	-13.4
SSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	8	-8
SSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	16	-16
SSTL-135	—	$V_{REF} - 0.09$	$V_{REF} + 0.09$	—	—	$V_{REF} - 0.16$	$V_{REF} + 0.16$	—	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	—	—
HSTL-18 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-18 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	16	-16
HSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	—	0.4	$V_{CCIO} - 0.4$	16	-16

continued...



Core Performance Specifications

Clock Tree Specifications

Table 26. Clock Tree Specifications for Intel MAX 10 Devices

Device	Performance					Unit
	-I6	-A6, -C7	-I7	-A7	-C8	
10M02	450	416	416	382	402	MHz
10M04	450	416	416	382	402	MHz
10M08	450	416	416	382	402	MHz
10M16	450	416	416	382	402	MHz
10M25	450	416	416	382	402	MHz
10M40	450	416	416	382	402	MHz
10M50	450	416	416	382	402	MHz

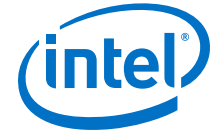
PLL Specifications

Table 27. PLL Specifications for Intel MAX 10 Devices

V_{CCD_PLL} should always be connected to V_{CCINT} through decoupling capacitor and ferrite bead.

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$f_{IN}^{(28)}$	Input clock frequency	—	5	—	472.5	MHz
f_{INPFD}	Phase frequency detector (PFD) input frequency	—	5	—	325	MHz
continued...						

(28) This parameter is limited in the Intel Quartus Prime software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.



Symbol	Parameter	Condition	Min	Typ	Max	Unit
f_{VCO} ⁽²⁹⁾	PLL internal voltage-controlled oscillator (VCO) operating range	—	600	—	1300	MHz
f_{INDUTY}	Input clock duty cycle	—	40	—	60	%
$t_{INJITTER_CCJ}$ ⁽³⁰⁾	Input clock cycle-to-cycle jitter	$F_{INPFD} \geq 100$ MHz	—	—	0.15	UI
		$F_{INPFD} < 100$ MHz	—	—	±750	ps
f_{OUT_EXT} ⁽²⁸⁾	PLL output frequency for external clock output	—	—	—	472.5	MHz
f_{OUT}	PLL output frequency to global clock	–6 speed grade	—	—	472.5	MHz
		–7 speed grade	—	—	450	MHz
		–8 speed grade	—	—	402.5	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output	Duty cycle set to 50%	45	50	55	%
t_{LOCK}	Time required to lock from end of device configuration	—	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically	After switchover, reconfiguring any non-post-scale counters or delays, or when areset is deasserted	—	—	1	ms
$t_{OUTJITTER_PERIOD_IO}$ ⁽³¹⁾	Regular I/O period jitter	$F_{OUT} \geq 100$ MHz	—	—	650	ps
		$F_{OUT} < 100$ MHz	—	—	75	mUI
$t_{OUTJITTER_CCJ_IO}$ ⁽³¹⁾	Regular I/O cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	—	—	650	ps
		$F_{OUT} < 100$ MHz	—	—	75	mUI

continued...

- ⁽²⁹⁾ The VCO frequency reported by the Intel Quartus Prime software in the PLL summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.
- ⁽³⁰⁾ A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source, which is less than 200 ps.
- ⁽³¹⁾ Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied.



Embedded Multiplier Specifications

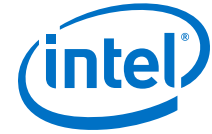
Table 30. Embedded Multiplier Specifications for Intel MAX 10 Devices

Mode	Number of Multipliers	Power Supply Mode	Performance			Unit
			-I6	-A6, -C7, -I7, -A7	-C8	
9 × 9-bit multiplier	1	Single supply mode	198	183	160	MHz
		Dual supply mode	310	260	210	MHz
18 × 18-bit multiplier	1	Single supply mode	198	183	160	MHz
		Dual supply mode	265	240	190	MHz

Memory Block Performance Specifications

Table 31. Memory Block Performance Specifications for Intel MAX 10 Devices

Memory	Mode	Resources Used		Power Supply Mode	Performance			Unit
		LEs	M9K Memory		-I6	-A6, -C7, -I7, -A7	-C8	
M9K Block	FIFO 256 × 36	47	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	Single-port 256 × 36	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	Simple dual-port 256 × 36 CLK	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	True dual port 512 × 18 single CLK	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz



Parameter		Symbol	Condition	Min	Typ	Max	Unit
Conversion Rate ⁽⁵²⁾	Conversion time	—	Single measurement	—	—	1	Cycle
			Continuous measurement	—	—	1	Cycle
			Temperature measurement	—	—	1	Cycle

Related Information

[SPICE Models for Intel FPGAs](#)

Periphery Performance Specifications

This section describes the periphery performance, high-speed I/O, and external memory interface.

Actual achievable frequency depends on design and system specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specifications

For more information about the high-speed and low-speed I/O performance pins, refer to the respective device pin-out files.

Related Information

[Documentation: Pin-Out Files for Intel FPGAs](#)

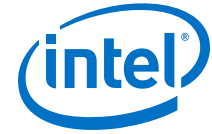
⁽⁵²⁾ For more detailed description, refer to the Timing section in the *Intel MAX 10 Analog-to-Digital Converter User Guide*.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵³⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x Jitter} ⁽⁵⁴⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵³⁾ TCCS specifications apply to I/O banks from the same side only.

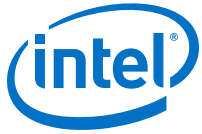
⁽⁵⁴⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×8	80	—	100	80	—	100	80	—	100	Mbps
		×7	70	—	100	70	—	100	70	—	100	Mbps
		×4	40	—	100	40	—	100	40	—	100	Mbps
		×2	20	—	100	20	—	100	20	—	100	Mbps
		×1	10	—	100	10	—	100	10	—	100	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵⁵⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _x Jitter ⁽⁵⁶⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵⁵⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁵⁶⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



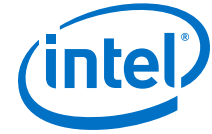
Dual Supply Devices True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications

Table 38. True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

True **RSDS** transmitter is only supported at bottom I/O banks. Emulated **RSDS** transmitter is supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	155	5	—	155	5	—	155	MHz
		×8	5	—	155	5	—	155	5	—	155	MHz
		×7	5	—	155	5	—	155	5	—	155	MHz
		×4	5	—	155	5	—	155	5	—	155	MHz
		×2	5	—	155	5	—	155	5	—	155	MHz
		×1	5	—	310	5	—	310	5	—	310	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	310	100	—	310	100	—	310	Mbps
		×8	80	—	310	80	—	310	80	—	310	Mbps
		×7	70	—	310	70	—	310	70	—	310	Mbps
		×4	40	—	310	40	—	310	40	—	310	Mbps
		×2	20	—	310	20	—	310	20	—	310	Mbps
		×1	10	—	310	10	—	310	10	—	310	Mbps
f _{HCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	150	5	—	150	5	—	150	MHz
		×8	5	—	150	5	—	150	5	—	150	MHz
		×7	5	—	150	5	—	150	5	—	150	MHz
		×4	5	—	150	5	—	150	5	—	150	MHz
		×2	5	—	150	5	—	150	5	—	150	MHz
		×1	5	—	300	5	—	300	5	—	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	300	100	—	300	100	—	300	Mbps
		×8	80	—	300	80	—	300	80	—	300	Mbps
		×7	70	—	300	70	—	300	70	—	300	Mbps

continued...



Symbol	Parameter	Mode	-C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

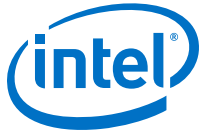
Dual Supply Devices True LVDS Transmitter Timing Specifications

Table 42. True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

True LVDS transmitter is only supported at the bottom I/O banks.

Symbol	Parameter	Mode	-I6			-A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HSCLK}	Input clock frequency	×10	5	—	360	5	—	340	5	—	310	5	—	300	MHz
		×8	5	—	360	5	—	360	5	—	320	5	—	320	MHz
		×7	5	—	360	5	—	340	5	—	310	5	—	300	MHz
		×4	5	—	360	5	—	350	5	—	320	5	—	320	MHz
		×2	5	—	360	5	—	350	5	—	320	5	—	320	MHz
		×1	5	—	360	5	—	350	5	—	320	5	—	320	MHz
HSIODR	Data rate	×10	100	—	720	100	—	680	100	—	620	100	—	600	Mbps
		×8	80	—	720	80	—	720	80	—	640	80	—	640	Mbps
		×7	70	—	720	70	—	680	70	—	620	70	—	600	Mbps
		×4	40	—	720	40	—	700	40	—	640	40	—	640	Mbps
		×2	20	—	720	20	—	700	20	—	640	20	—	640	Mbps

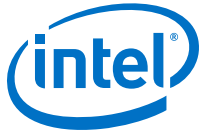
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Symbol	Parameter	Mode	-I6			-A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×1	10	—	360	10	—	350	10	—	320	10	—	320	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁶⁵⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	—	—	300	ps
t _x Jitter ⁽⁶⁶⁾	Output jitter	—	—	—	380	—	—	380	—	—	380	—	—	380	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	—	—	1	ms

⁽⁶⁵⁾ TCCS specifications apply to I/O banks from the same side only.

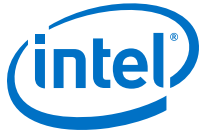
⁽⁶⁶⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×8	80	—	200	80	—	200	80	—	200	Mbps
		×7	70	—	200	70	—	200	70	—	200	Mbps
		×4	40	—	200	40	—	200	40	—	200	Mbps
		×2	20	—	200	20	—	200	20	—	200	Mbps
		×1	10	—	200	10	—	200	10	—	200	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁶⁷⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁶⁸⁾	Output jitter	—	—	—	1,000	—	—	1,000	—	—	1,000	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(67) TCCS specifications apply to I/O banks from the same side only.

(68) TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
	Sampling window (low-speed I/O performance pin)	—	—	910	—	910	—	910	ps
$t_{x \text{ Jitter}}^{(72)}$	Input jitter	—	—	500	—	500	—	500	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Memory Standards Supported by the Soft Memory Controller

Table 47. Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices

Contact your local sales representatives for access to the -I6 or -A6 speed grade devices in the Intel Quartus Prime software.

External Memory Interface Standard	Rate Support	Speed Grade	Voltage (V)	Max Frequency (MHz)
DDR3 SDRAM	Half	-I6	1.5	303
DDR3L SDRAM	Half	-I6	1.35	303
DDR2 SDRAM	Half	-I6	1.8	200
		-I7 and -C7		167
LPDDR2 ⁽⁷³⁾	Half	-I6	1.2	200 ⁽⁷⁴⁾

Related Information

External Memory Interface Spec Estimator

Provides the specific details of the memory standards supported.

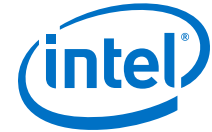
⁽⁷²⁾ TX jitter is the jitter induced from core noise and I/O switching noise.

⁽⁷³⁾ Intel MAX 10 devices support only single-die LPDDR2.

⁽⁷⁴⁾ To achieve the specified performance, constrain the memory device I/O and core power supply variation to within $\pm 3\%$. By default, the frequency is 167 MHz.



Date	Version	Changes
January 2016	2016.01.22	• Added description about automotive temperature devices in the Programming/Erasure Specifications table. • Changed the pin capacitance to maximum values. • Updated maximum TCCS specifications from 410 ps to 300 ps in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices • Added new table: True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices. • Updated maximum f_{HCLK} and HSIO DR specifications for –A6, –C7, and –I7 speed grades in True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Updated SW specifications in the following tables: — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices • Updated maximum f_{HCLK} and HSIO DR (high-speed I/O performance pin) specifications for –I6, –A6, –C7, –I7 speed grades in LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Removed Internal Configuration Time information in the Uncompressed .rbf Sizes for Intel MAX 10 Devices table. • Added Internal Configuration Time tables for uncompressed .rbf files and compressed .rbf files. • Removed Preliminary tags for all tables.
November 2015	2015.11.02	• Added description to <i>Maximum Allowed Overshoot During Transitions over a 11.4-Year Time Frame</i> topic. • Added ADC_VREF Pin Leakage Current for Intel MAX 10 Devices table. • Updated the condition for "Bus-hold high, sustaining current" parameter from "$V_{IN} < V_{IL}$ (minimum)" to "$V_{IN} < V_{IH}$ (minimum)" in Bus Hold Parameters table.
continued...		



Date	Version	Changes
		- Updated TCCS specifications in the following tables: - True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices - Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Updated $t_{x \text{ jitter}}$ specifications in the following tables: - True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices - Updated SW specifications in LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices table. - Added a note to $t_{x \text{ jitter}}$ for all LVDS tables. Note: TX jitter is the jitter induced from core noise and I/O switching noise. - Updated the description for t_{LOCK} for all LVDS tables: Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration. - Updated Memory Output Clock Jitter Specifications section. - Updated maximum external memory interfaces frequency from 300 MHz to 303 MHz. - Updated PLL output routing from global clock network to PHY clock network. - Added I/O Timing for Intel MAX 10 Devices table. - Added V_{HYS} in the Glossary table.
January 2015	2015.01.23	- Removed a note to V_{CCA} in Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices table. This note is not valid: All V_{CCA} pins must be connected together for EQFP package. - Corrected the maximum value for $t_{\text{OUTJITTER_CCJ_IO}}$ ($F_{\text{OUT}} \geq 100 \text{ MHz}$) from 60 ps to 650 ps in PLL Specifications for Intel MAX 10 Devices table.
December 2014	2014.12.15	- Restructured Programming/Erase Specifications for Intel MAX 10 Devices table to add temperature specifications that affect the data retention duration. - Added statements in the I/O Pin Leakage Current section: Input channel leakage of ADC I/O pins due to hot socket is up to maximum of 1.8 mA. The input channel leakage occurs when the ADC IP core is enabled or disabled. This is applicable to all Intel MAX 10 devices with ADC IP core, which are 10M04, 10M08, 10M16, 10M25, 10M40, and 10M50 devices. The ADC I/O pins are in Bank 1A. - Added a statement in the I/O Standards Specifications section: You must perform timing closure analysis to determine the maximum achievable frequency for general purpose I/O standards.

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